Notice of References Cited

| | Application/Control No. | Applicant(s)/Pater | nt Under |
|---|-------------------------|--------------------------------|-------------|
| | 10/506,914 | Reexamination MAXTED ET AL. | |
| | Examiner | Art Unit | |
| ı | Michael E. Nelson | 4174 | Page 1 of 1 |

II S PATENT DOCUMENTS

| | U.S. PATENT DOCUMENTS | | | | |
|---|-----------------------|--|-----------------|-------------------|----------------|
| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
| * | Α | US-4,834,505 A | 05-1989 | Migliorato et al. | 349/48 |
| * | В | US-6,150,043 A | 11-2000 | Thompson et al. | 428/690 |
| * | С | US-6,696,181 B2 | 02-2004 | Okunaka et al. | 428/690 |
| | D | US- | | | |
| | Е | US- | | | |
| | F | US- | | | |
| | G | US- | | - | |
| | Н | US- | | - | |
| | Т | US- | | | |
| | J | US- | | | |
| | К | US- | | | |
| | L | US- | | | |
| | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| | FOREIGN FATENT DOCUMENTS | | | | | |
|---|--------------------------|--|-----------------|---------|---------------|----------------|
| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
| | N | JP 2000-256319 | 09-2000 | Japan | Nakaya et al. | |
| | 0 | | | | | |
| | Р | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | s | | | | | |
| | Т | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|--|
| | U | Lamansky et al., "Molecularly doped polymer light emitting diodes utilizing phosphorescent Pt(II) and Ir(III) dopants," Organic Electronics, vol. 2, no. 1, pp. 53-62, March 2001. |
| | v | D/Andrade et al., "Controlling Exciton Diffusion in Multilayer White Phosphorescent Organic Light Emitting Devices," Advanced Materials, vol. 14, no. 2, pp. 147-151, Jan 2002. |
| | w | |
| | x | |

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.